

High-level fault diagnosis in RISC processors with Implementation-Independent Functional Test

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Implementation-independent functional test generation for RISC microprocessors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 82-87 : ill <https://doi.org/10.1109/VLSI-SoC.2019.8920323>

Minimization of the high-level fault model for microprocessor control parts [Online resource]

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen; Medaiyese, Olusiji BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p.: ill <https://doi.org/10.1109/BEC.2018.8600980>

On test generation for microprocessors for extended class of functional faults

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan VLSI-SoC: New technology enabler : 27th IFIP WG 10.5/IEEE International Conference on Very Large Scale Integration, VLSI-SoC 2019 Cusco, Peru, October 6-9, 2019 : Revised and Extended Selected Papers 2020 / p. 21-44 <https://doi.org/10.1007/978-3-030-53273-4> [Conference proceedings at Scopus](#)
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